

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Mieher, et al.

Attorney Docket No.: KLA1P117X1B/
1151 CIP2

Application No.: 10/785,395

Examiner: Gordon J. Stock Jr.

Filed: February 23, 2004

Group: 2877

Title: APPARATUS AND METHODS FOR
DETECTING OVERLAY ERRORS USING
SCATTEROMETRY

Confirmation No.: 6514

AMENDMENT B

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

It is respectfully submitted that the Examiner enters the following amendments in response to the Final Office Action dated 8 March 2007, a response to which is due 8 June 2007. It is noted that the current response is being submitted within two months of the mailing date of such Final Office Action.

Amendments to the Claims are reflected in the listing of claims which begin on page 2 of this paper.

Remarks/Arguments begin on page 5 of this paper.